## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Mitsuaki Osame et al. Art Unit : 2821 Serial No. : 10630,939 Examiner : David Hung Vu Filed : July 31, 2003 Conf. No. : 1228

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MAIL STOP RCE Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Submitted herewith is an English translation of the following foreign language reference, or portions thereof:

Desig. 1D	Source	
AL	WO98/36407 – English Abstract: esp@cenet.com.	
AM	EP 0 895 219A1 – Full English language translation and family to WO98/36407 (Desig. ID "AL").	

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date:November 9, 2006	/Diana DiBerardino/
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Substitute Disclosure Form (PTO-1449)

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-161001	Application No. 10/630,939
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.96(b))		Appleant Mitsuaki Osame et al.	
		Fring Date July 31, 2003	Group Art Unit 2821

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0196206	12-26-2002	Kimura et al.			08/21/2002
	AB	2003/0098827	05-29-2003	Ozawa et al.			10/10/2002
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	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document			
	AQ				
	AR				
	AS				
	AT				

Examiner Signature	Date Considered					
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with						
next communication to applicant.						